

Date Created : 2008/04/02
Date Issued On : 2008/04/28
PCN# : Q2081402

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A Final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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Implementation of change:

Expected 1st Device Shipment Date: 2008/08/02

Earliest Year/Work Week of Changed Product: 0832

Change Type Description: Alternate Fab Location

Description of Change (From): Optoelectronics detector devices utilized in the assembly of the attached affected products are currently fabricated at China Resources (CRS) 4 inch fabrication facility located in Hong Kong, China.

Description of Change (To): Optoelectronics detector devices utilized in the assembly of the attached affected products will be fabricated at CRS 6 inch fabrication facility located in Wuxi, China. There will be no detector device, design, die size or die thickness changes for the affected FSID's. Product assembled with detector die manufactured at Wuxi facility will be fully compliant to all publish databook specifications and will be interchangeable with products manufactured at the existing wafer fab location. Quality and reliability will remain at the highest levels already demonstrated with Fairchild existing products.

Reason for Change : Optoelectronic detector devices utilized in the assembly of the attached list of affected products will no longer be fabricated in CRS Hong Kong facility. The planned transfer from CRS Hong Kong facility to their fabrication facility in Wuxi, China may impact the ability to supply existing qualified product during the routine PCN approval cycle for certain affected products. Fairchild will work with customer to manage any identified supply issues that may arise.

Qual/REL Plan Numbers : Q20080075

Qualification :

This is to qualified 6 inch fab process in CRS Wuxi

Qualification Stress Test and Sample Size Detail

Device #1	6N137
Package:	
#Leads:	-1

Precondition Description:

				Read-points	Sample		
Stress	P/C	Standard	Conditions		A	B	C
PCOPTO 1C		JESDSS-A113			0	0	0

Environment Stress Detail:

				Readpoints			Samples		
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
ACLV		JESD22-A102	100%RH, 121C	96			45	45	45
HTOL	X		100C	168	500	1000	45	45	45
HTRB	X	JESD22-A108	85C, 4V	168	500	1000	45	45	45
HTSL	X	JESD22-A103	125C	168	500	1000	45	45	45
LTS			-55C	168	500	1000	45	45	45
THBT	X	JESD22-A101	85%RH, 85C, 4V	168	500	1000	45	45	45
TMCL2	X	JESD22-A104	-55C, 125C	100	200	500	45	45	45

Device #2	FODM3052
Package:	-1
#Leads:	-1

Precondition Description:

				Read-points	Sample		
Stress	P/C	Standard	Conditions		A	B	C
PCOPTO 1B		JESD22-A113			0	0	0

Environment Stress Detail:

				Readpoints			Samples		
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
ACLV		JESD22-A102	100%RH, 121C	96			45	45	45
HTOL	X		100C	168	500	1000	45	45	45
HTRB	X	JESD22-A108	100C, 480V	168	500	1000	45	45	45
HTSL	X	JESD22-A103	150C	168	500	1000	45	45	45
LTS			-55C	168	500	1000	45	45	45
THBT	X	JESD22-A101	85%RH, 85C, 100V	168	500	1000	45	45	45
TMCL2	X	JESD22-A104	-55C, 125C	100	200	500	45	45	45

Device #3	H11F1M
Package:	
#Leads:	-1

Precondition Description:

				Read-points	Sample		
Stress	P/C	Standard	Conditions		A	B	C
PCOPTO 1B		JESD22-A113			0	0	0

Environment Stress Detail:

				Readpoints			Samples		
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Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
ACLV		JESD22-A102	100%RH, 121C	96			45	45	45
HTOL	X		100C	168	500	1000	45	45	45
HTRB	X	JESD22-A108	100C, 24V	168	500	1000	45	45	45
HTSL	X	JESD22-A103	150C	168	500	1000	45	45	45
LTS			-55C	168	500	1000	45	45	45
THBT	X	JESD22-A101	85%RH, 85C, 24V	168	500	1000	45	45	45
TMCL2	X	JESD22-A104	-40C, 125C	100	200	500	45	45	45

Device #4	HCPL0600
Package:	
#Leads:	-1

Precondition Description:

				Read-points	Sample		
Stress	P/C	Standard	Conditions		A	B	C
PCOPTO 1B		JESD22-A113			0	0	0

Environment Stress Detail:

				Readpoints			Samples		
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
ACLV		JESD22-A102	100%RH, 121C	96			45	45	45
HTOL	X		85C	168	500	1000	45	45	45
HTRB	X	JESD22-A108	100C, 4V	168	500	1000	45	45	45
HTSL	X	JESD22-A103	125C	168	500	1000	45	45	45
HTSL	X	JESD22-A103	150C	168	500	1000	45	45	45
LTS			-40C	168	500	1000	45	45	45
THBT	X	JESD22-A101	85%RH, 85C, 4V	168	500	1000	45	45	45
TMCL2	X	JESD22-A104	-40C, 125C	100	200	500	45	45	45

Device #5	MOC3052M
Package:	
#Leads:	-1

Precondition Description:

				Read-points	Sample		
Stress	P/C	Standard	Conditions		A	B	C
PCOPTO 1B		JESD22-A113			0	0	0

Environment Stress Detail:

				Readpoints			Samples		
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
ACLV		JESD22-A102	100%RH, 121C	96			45	45	45
HTOL	X		85C	168	500	1000	45	45	45
HTRB	X	JESD22-A108	85C, 480V	168	500	1000	45	45	45
HTSL	X	JESD22-A103	150C	168	500	1000	45	45	45
LTS			-40C	168	500	1000	45	45	45
THBT	X	JESD22-A101	85%RH, 85C, 100V	168	500	1000	45	45	45
TMCL2	X	JESD22-A104	-40C, 125C	100	200	500	45	45	45

Device #6	MOC8204M
Package:	
#Leads:	-1

Precondition Description:

				Read-points	Sample		
Stress	P/C	Standard	Conditions		A	B	C
PCOPTO 1B		JESD22-A113			0	0	0

Environment Stress Detail:

				Readpoints			Samples		
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
ACLV		JESD22-A102	100%RH, 121C	96			45	45	45
HTOL	X		100C	168	500	1000	45	45	45
HTRB	X	JESD22-A108	85C, 320V	168	500	1000	45	45	45
HTSL	X	JESD22-A103	150C	168	500	1000	45	45	45
LTS			-55C	168	500	1000	45	45	45
THBT	X	JESD22-A101	85%RH, 85C, 100V	168	500	1000	45	45	45
TMCL2	X	JESD22-A104	-40C, 125C	100	200	500	45	45	45

Device #7	MOCD223M
Package:	
#Leads:	-1

Precondition Description:

				Read-points	Sample		
Stress	P/C	Standard	Conditions		A	B	C
PCOPTO 1B		JESD22-A113			0	0	0

Environment Stress Detail:

				Readpoints			Samples		
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
ACLV		JESD22-A102	100%RH, 121C	96			45	45	45
HTOL	X		100C	168	500	1000	45	45	45
HTRB	X	JESD22-A108	100C, 24V	168	500	1000	45	45	45
HTSL	X	JESD22-A103	150C	168	500	1000	45	45	45
LTS			-40C	168	500	1000	45	45	45
THBT	X	JESD22-A101	85%RH, 85C, 24V	168	500	1000	45	45	45
TMCL2	X	JESD22-A104	-40C, 125C	100	200	500	45	45	45

Device #8	QSE133
Package:	-1
#Leads:	-1

Environment Stress Detail:

				Readpoints			Samples		
Stress	P/C	Standard	Conditions	TP1	TP2	TP3	A	B	C
HTOL			100C	168	500	1000	45	45	45
HTRB		JESD22-A108	85C, 24V	168	500	1000	45	45	45
HTSL		JESD22-A103	100C	168	500	1000	45	45	45
LTS			-40C	168	500	1000	45	45	45

THBT		JESD22-A101	85%RH, 85C, 24V	168	500	1000	45	45	45
TMCL2		JESD22-A104	-40C, 100C	100	200	500	45	45	45

Product Id Description :

Affected FSIDs :

4N38M	4N38SR2M	FOD2200
FOD2200S	FOD2200SD	FOD2200SDV
FOD2200SV	FOD2200T	FOD2200TV
FOD2200V	H11AG1M	H11AG1SM
H11AG1SR2M	H11AG1TVM	H11AG1VM
MCT5201M	MCT5201SM	MCT5201SR2M
MCT5210M	MCT5210SM	MCT5211M
MCT5211SR2M	MCT5211SVM	MOC3051M
MOC3051SM	MOC3051SR2M	MOC3051SR2VM
MOC3051SVM	MOC3051TM	MOC3051TVM
MOC3051VM	MOC3052M	MOC3052SM
MOC3052SR2M	MOC3052SR2VM	MOC3052SVM
MOC3052TM	MOC3052TVM	MOC3052VM
MOC8204M	MOC8204SM	MOC8204SR2M
TIL113M	TIL113SM	